S/N 09/901001 PATENT

## N THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Kie Y. Ahn et al.

Examiner:

Kathleen Duda

Serial No.:

09/901001

Group Art Unit:

1756

Filed:

July 09, 2001

Docket:

1303.016US1

Title:

COPPER ELECTROLESS DEPOSITION TECHNOLOGY FOR ULSI METALIZATION

## INFORMATION DISCLOSURE STATEMENT

MS RCE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

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By their Representatives,

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<u>CERTIFICATE UNDER 37 CFR 1.8:</u> The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 21st day of November, 2003.

Hmy Moriarty

Signature

Substitute for form 1449A/PTO
INFORMATION DISCLOSURE
STATEMENT BY APPEICANT
(Use as many sheets as necessary)

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Sheet 1 of 1

Under the Paperwork Reduction Act of 1995, no persons are Complete if Known	required to respond to a collection of information unless it	contains a valid OMB control number
Application Number	09/901001	
Filing Date	July 9, 2001	
First Named Inventor	Ahn, Kie	
Group Art Unit	1756	
Examiner Name	Duda, Kathleen	18
		<u> </u>

Attorney Docket No: 1303.016US1

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	OTHE	R DOCUMENTS NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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**EXAMINER** 

**DATE CONSIDERED**